

# N-Channel 100 V (D-S) 175 °C MOSFET

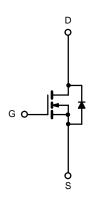
PRODUCT SUMMARY					
V <sub>DS</sub> (V)	$R_{DS(on)}$ ( $\Omega$ )	I <sub>D</sub> (A)			
100	0.006 at V <sub>GS</sub> = 10 V	150			

#### **FEATURES**

- TrenchFET® Power MOSFET
- New Package with Low Thermal Resistance
- 100 % R<sub>g</sub> Tested







N-Channel MOSFET

<b>ABSOLUTE MAXIMUM RATINGS</b> $T_C = 25$ °C, unless otherwise noted						
Parameter	Symbol	Limit	Unit			
Drain-Source Voltage	V <sub>DS</sub>	100	M			
Gate-Source Voltage	V <sub>GS</sub>	± 20	V			
Continuous Danis Compant (T., 475 °C)	T <sub>C</sub> = 25 °C		150	^		
Continuous Drain Current (T <sub>J</sub> = 175 °C)	T <sub>C</sub> = 125 °C	l lo	100 <sup>a</sup>			
Pulsed Drain Current	I <sub>DM</sub>	600	А			
Avalanche Current	I <sub>AR</sub>	75				
Repetitive Avalanche Energy <sup>b</sup>	L = 0.1 mH	E <sub>AR</sub>	280	mJ		
Maximum Power Dissipation <sup>b</sup>	T <sub>C</sub> = 25 °C	В	375 <sup>c</sup>	W		
Maximum Fower Dissipation	T <sub>A</sub> = 25 °C	$P_{D}$	3.75	VV		
Operating Junction and Storage Temperatu	T <sub>J</sub> , T <sub>stg</sub>	- 55 to 175	°C			

THERMAL RESISTANCE RATINGS						
Parameter	Symbol	Limit	Unit			
Junction-to-Ambient	TO-247	R <sub>thJA</sub>	40	°C/W		
Junction-to-Case (Drain)		R <sub>thJC</sub>	0.5	C/VV		

#### Notes:

- a. Package limited.
- b. Duty cycle ≤ 1 %.
  c. See SOA curve for voltage derating.

服务热线:400-655-8788

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Parameter	Symbol	Test Conditions	Min.	Тур.	Max.	Unit	
Static							
Drain-Source Breakdown Voltage	V <sub>DS</sub>	$V_{DS} = 0 \text{ V}, I_{D} = 250  \mu\text{A}$	100				
Gate-Threshold Voltage	V <sub>GS(th)</sub>	$V_{DS} = V_{GS}, I_{D} = 250 \mu A$	2		4	V	
Gate-Body Leakage	I <sub>GSS</sub>	$V_{DS} = 0 \text{ V}, V_{GS} = \pm 20 \text{ V}$			± 100	nA	
		V <sub>DS</sub> = 100 V, V <sub>GS</sub> = 0 V			1	1 50 μA 250	
Zero Gate Voltage Drain Current	I <sub>DSS</sub>	V <sub>DS</sub> = 100 V, V <sub>GS</sub> = 0 V, T <sub>J</sub> = 125 °C			50		
		V <sub>DS</sub> = 100 V, V <sub>GS</sub> = 0 V, T <sub>J</sub> = 175 °C			250		
On-State Drain Current <sup>a</sup>	I <sub>D(on)</sub>	$V_{DS} \ge 5 \text{ V}, V_{GS} = 10 \text{ V}$	120			Α	
		V <sub>GS</sub> = 10 V, I <sub>D</sub> = 30 A		0.006		Ω	
Drain-Source On-State Resistance <sup>a</sup>	R <sub>DS(on)</sub>	V <sub>GS</sub> = 10 V, I <sub>D</sub> = 30 A, T <sub>J</sub> = 125 °C		0.017			
		V <sub>GS</sub> = 10 V, I <sub>D</sub> = 30 A, T <sub>J</sub> = 175 °C		0.025		1	
Forward Transconductance <sup>a</sup>	9 <sub>fs</sub>	V <sub>DS</sub> = 15 V, I <sub>D</sub> = 30 A	25			S	
Dynamic <sup>b</sup>							
Input Capacitance	C <sub>iss</sub>			6700		pF	
Output Capacitance	C <sub>oss</sub>	$V_{GS} = 0 \text{ V}, V_{DS} = 25 \text{ V}, f = 1 \text{ MHz}$		750			
Reverse Transfer Capacitance	C <sub>rss</sub>			280			
Total Gate Charge <sup>c</sup>	Qg			110	160	nC	
Gate-Source Charge <sup>c</sup>	Q <sub>gs</sub>	$V_{DS} = 50 \text{ V}, V_{GS} = 10 \text{ V}, I_{D} = 85 \text{ A}$		24			
Gate-Drain Charge <sup>c</sup>	$Q_{gd}$			24			
Gate Resistance	R <sub>g</sub>		1.0		6.2	Ω	
Turn-On Delay Time <sup>c</sup>	t <sub>d(on)</sub>			20	30		
Rise Time <sup>c</sup>	t <sub>r</sub>	$V_{DD} = 50 \text{ V, R}_{L} = 0.6 \Omega$		125	200	no	
Turn-Off Delay Time <sup>c</sup>	t <sub>d(off)</sub>	$I_D \cong 85 \text{ A}, V_{GEN} = 10 \text{ V}, R_g = 2.5 \Omega$		55	85	ns ns	
Fall Time <sup>c</sup>	t <sub>f</sub>			130	195		
Source-Drain Diode Ratings and Cha	aracteristics 7	T <sub>C</sub> = 25 °C <sup>b</sup>					
Continuous Current	I <sub>S</sub>				110	٨	
Pulsed Current	I <sub>SM</sub>				240	Α	
Forward Voltage <sup>a</sup>	V <sub>SD</sub>	I <sub>F</sub> = 85 A, V <sub>GS</sub> = 0 V		1.0	1.5	V	
Reverse Recovery Time	t <sub>rr</sub>			70	140	ns	
Peak Reverse Recovery Charge	I <sub>RM(REC)</sub>	I <sub>F</sub> = 50 A, dl/dt = 100 A/μs		5.5	10	Α	
Reverse Recovery Charge	Q <sub>rr</sub>	7		0.19	0.35	μC	

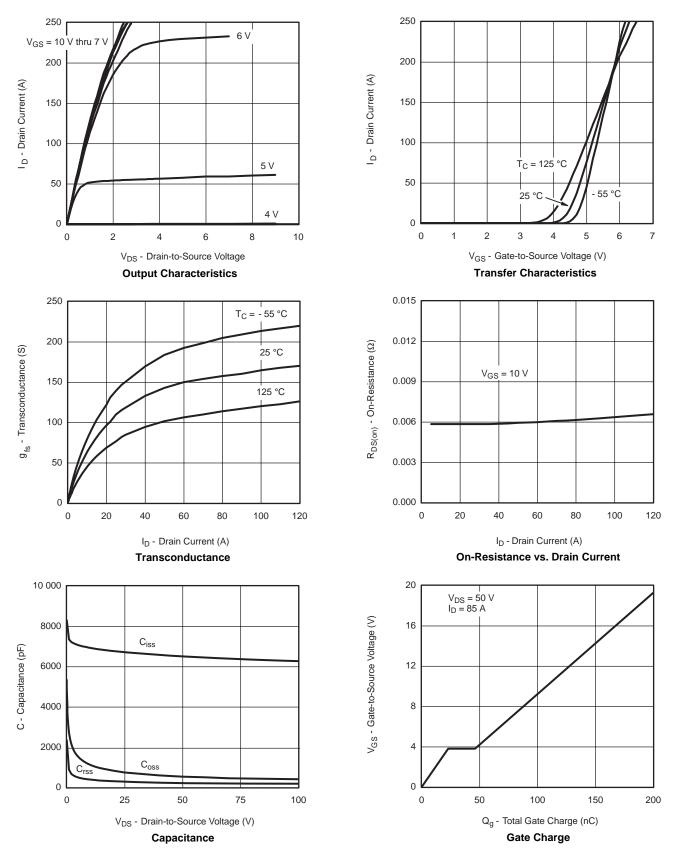
#### Notes:

- a. Pulse test; pulse width  $\leq$  300 µs, duty cycle  $\leq$  2 %.
- b. Guaranteed by design, not subject to production testing.
- c. Independent of operating temperature.

Stresses beyond those listed under "Absolute Maximum Ratings" may cause permanent damage to the device. These are stress ratings only, and functional operation of the device at these or any other conditions beyond those indicated in the operational sections of the specifications is not implied. Exposure to absolute maximum rating conditions for extended periods may affect device reliability.

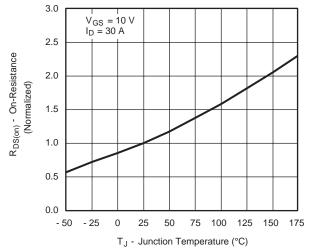


### TYPICAL CHARACTERISTICS 25 °C, unless otherwise noted

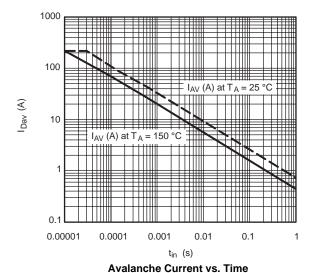




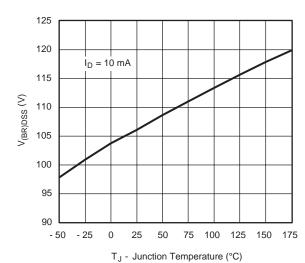
### TYPICAL CHARACTERISTICS 25 °C, unless otherwise noted



## On-Resistance vs. Junction Temperature



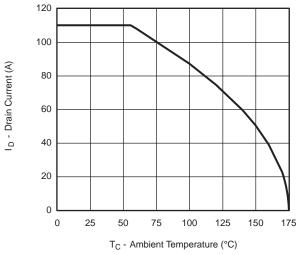
## Source-Drain Diode Forward Voltage



Drain Source Breakdown vs. Junction Temperature

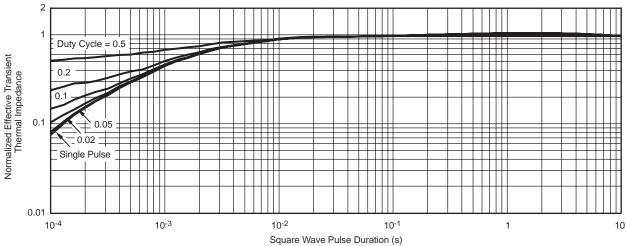


#### THERMAL RATINGS



 $(V_{DS} - Drain-to-Source Voltage (V) \\ V_{GS} > minimum V_{GS} at which R_{DS(on)} is specified \\ Safe Operating Area \\ (V_{DS} - Drain-to-Source) \\ Safe Operating Area \\ (V_{DS} - Drain-to-Source) \\ Safe Operating Area \\ (V_{DS} - Drain-to-Source) \\ (V_{DS} - Drain-to-Sour$ 

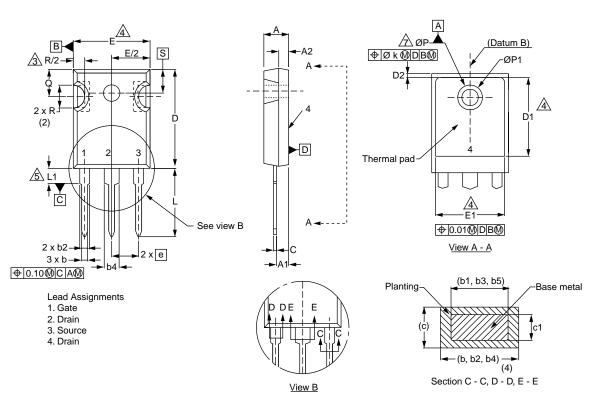
Maximum Avalanche and Drain Current vs. Case Temperature



Normalized Thermal Transient Impedance, Junction-to-Case



## **TO-247AC**



	MILLIMETERS		INC	HES
DIM.	MIN.	MAX.	MIN.	MAX.
Α	4.58	5.31	0.180	0.209
A1	2.21	2.59	0.087	0.102
A2	1.17	2.49	0.046	0.098
b	0.99	1.40	0.039	0.055
b1	0.99	1.35	0.039	0.053
b2	1.53	2.39	0.060	0.094
b3	1.65	2.37	0.065	0.093
b4	2.42	3.43	0.095	0.135
b5	2.59	3.38	0.102	0.133
С	0.38	0.86	0.015	0.034
c1	0.38	0.76	0.015	0.030
D	19.71	20.82	0.776	0.820
D1	13.08	-	0.515	-

	MILLIM	IETERS	INC	HES	
DIM.	MIN.	MAX.	MIN.	MAX.	
D2	0.51	1.30	0.020	0.051	
E	15.29	15.87	0.602	0.625	
E1	13.72	-	0.540	-	
е	5.46	BSC	0.215 BSC		
Øk	0.2	0.254		0.010	
L	14.20	16.25	0.559	0.640	
L1	3.71	4.29	0.146	0.169	
N	7.62 BSC		0.300 BSC		
ØΡ	3.51	3.66	0.138	0.144	
Ø P1	-	7.39	-	0.291	
Q	5.31	5.69	0.209	0.224	
R	4.52	5.49	0.178	0.216	
S	5.51 BSC		0.217	BSC	



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